SMD TEST FIXTURE IM9110

Designed for Simplicity and Reliability

LCR measurement of 008004 size* SMDs

*EIA unit: inch (0.25 mm × 0.125 mm)

Compatible LCR instruments:
IM3590, IM3570, IM3536, IM3533, IM3523, 3511-50, 3506-10
3532-50 (legacy product), 3522-50 (legacy product)

Information current as of March 2016. Please contact Hioki for the latest information about supported models.
Easily place samples via built-in cover that keeps the sample from popping out

**Loading samples**

1. Move the control lever to the “OPEN” position.

2. Place the sample in the guide groove.

3. Move the control lever to the “CLOSE” position to lock the sample in place.

**Probe contact**

- Measurement probe diameter: \( \phi 0.155 \) mm
- Guide groove: 0.16 mm
- Shape of probe tip: 60° cone

Advanced contact technology delivers highly reproducible measurement results.

**Specifications**

- **Operating temperature and humidity**: 0°C to 40°C (32°F to 104°F), 80% RH or less (no condensation)
- **Storage temperature and humidity**: -10°C to 55°C (14°F to 131°F), 80% RH or less (no condensation)
- **Dimensions**: Approx. 99 mm (3.9 in) W x 42 mm (1.65 in) H x 73 mm (2.87 in) D (Excluding control lever, lock lever, and micrometer)
- **Mass**: Approx. 270 g (9.5 oz)
- **Product warranty**: 1 year
- **Connection with sample**: 2-terminal connection from opposite sides
- **Measurable sample dimensions**: 0.25 ±20% × 0.125 ±10% × 0.125 ±10% mm (EIA size category: 008004)
- **Maximum applied voltage**: ±42 V peak (AC+DC)
- **Maximum applied current**: 0.15 Arms (±0.15 A DC)
- **Usable frequency range**: DC to 1 MHz
- **Residual parameter values**
  - Capacitance: \( C < 35 \) fF (With 0.25 mm between measurement probes)
  - Inductance: \( L < 120 \) nH (2-terminal contact while using short compensation fixture)
  - Resistance: \( R < 800 \) mΩ (2-terminal contact while using short compensation fixture)
- **Contact pressure on sample**: 0.14 N (15 gf) or less
- **Measurement probe distance setting**: Set using a micrometer with a 0.01 mm graduated scale. (Inclusion of a micrometer allows the distance between measurement probes to be set easily. In particular, open compensation can be performed without a measurement sample.)
- **Connection to instrument**: 4-terminal pair (Connector: BNC; distance between connectors: 22 mm)
- **Accessories**: User manual, short compensation fixture x 3, cleaning brush

**Product Name**: SMD TEST FIXTURE IM9110

**Model No. (Order Code)**

IM9110

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**IM9110E2-67E**  Printed in Japan